

Preparation and characterization of laboratory samples

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UNIVERSITY OF HELSINKI

Outline

- Milling
- Sieving
- Measuring size distribution
- Characterizing the structure: SEM and FESEM
- Laboratory daily procedures (safety and cleaning)

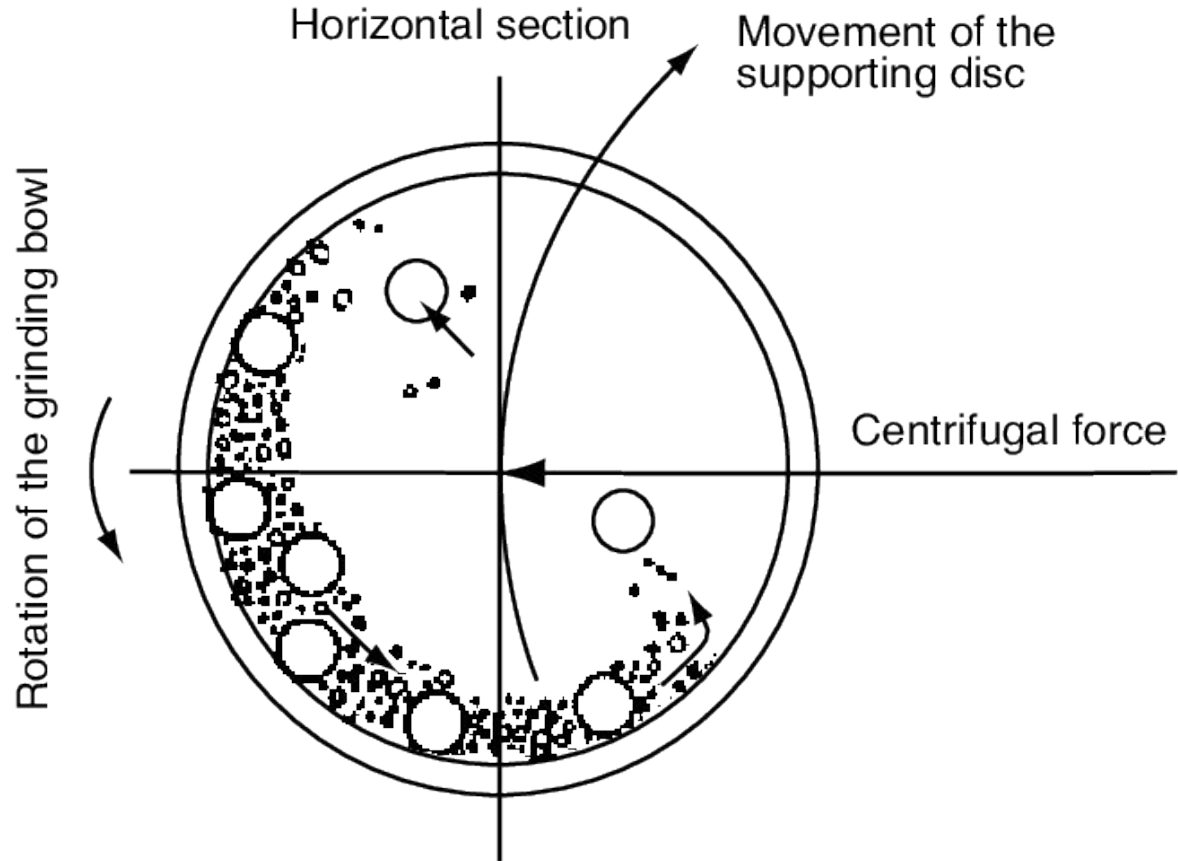
Milling

Milling: ball milling



Ball mill

Milling: ball milling



Milling: ball milling

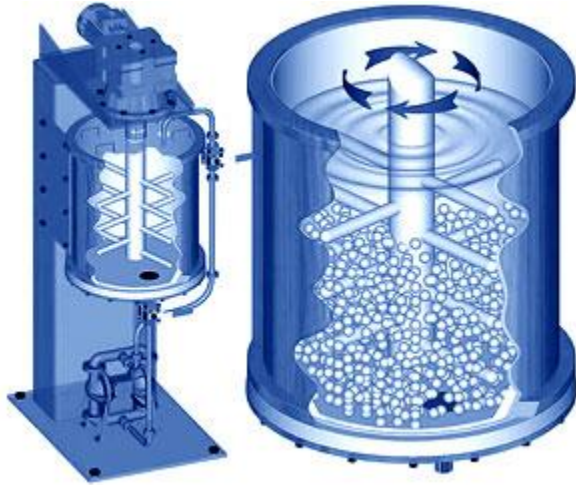
Advantages:

- It produces very fine powder (particle size less than or equal to 10 microns).
- It is suitable for milling toxic materials since it can be used in a completely enclosed form.
- Has a wide application.
- It can be used for continuous operation.
- It is used in milling highly abrasive materials.

Disadvantages:

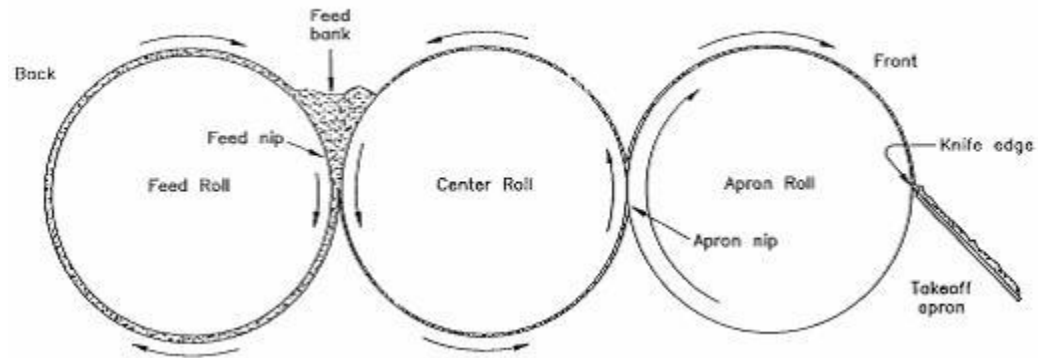
- Contamination of product may occur as a result of wear and tear which occurs principally from the balls and partially from the casing.
- High machine noise level especially if the hollow cylinder is made of metal, but much less if rubber is used.
- Relatively long time of milling.
- It is difficult to clean the machine after use.

Milling : attrition milling



- Commonly used grinding media types are stainless steel, chrome steel, tungsten carbide, ceramic, or zirconium oxide.
- The material and the media are then agitated by the shaft with cross arms, rotating at high speed.
- This causes the media to exert both shearing and impact forces on the material, resulting in optimum size reduction and dispersion.
- No premixing is necessary. The material can be directly fed into the jacketed grinding tank of the mill.
- The final result of the grinding action is a fine, even particle dispersion.
- Temperature control (either cooling or heating) can be maintained with the use of jacketed tanks.

Milling : roll mill



Sieving

Dry sieving



Different sieve sizes



Sieve shaker

Wet sieving

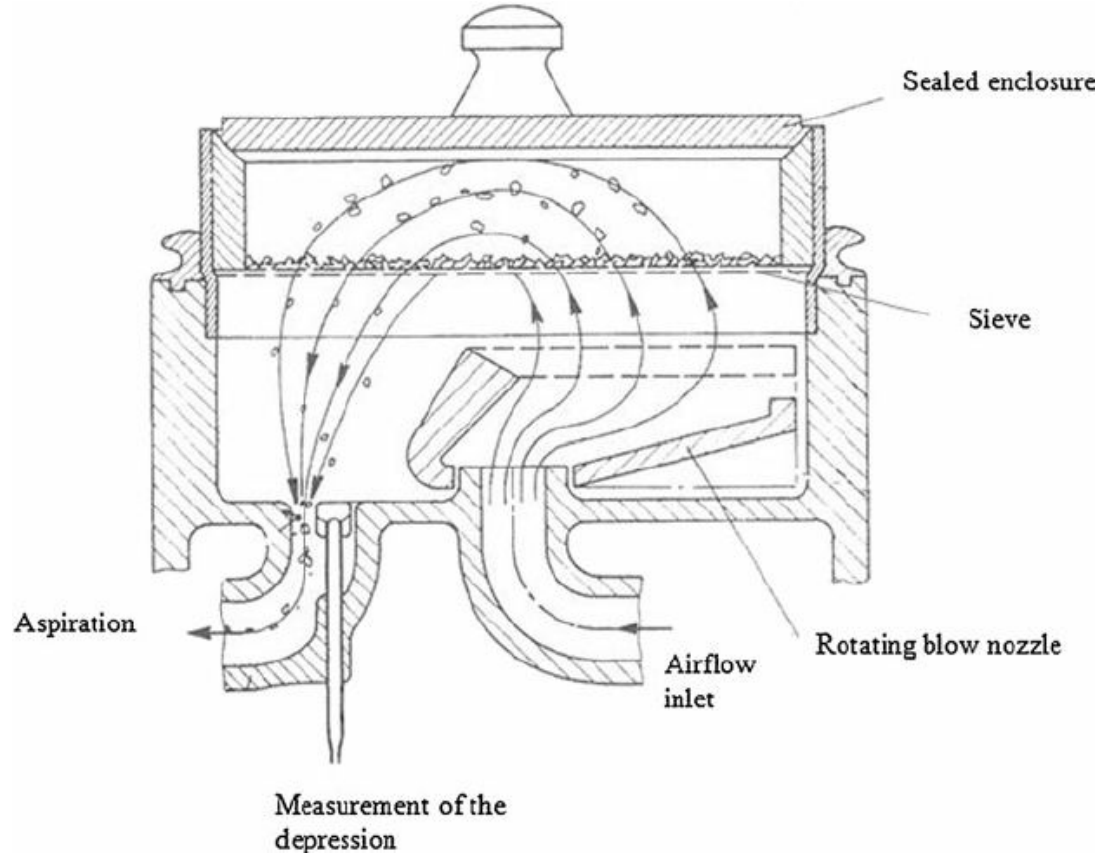


It is used when the sample tends to aggregate. To recover the smallest particles we have to let dry the water remanent.

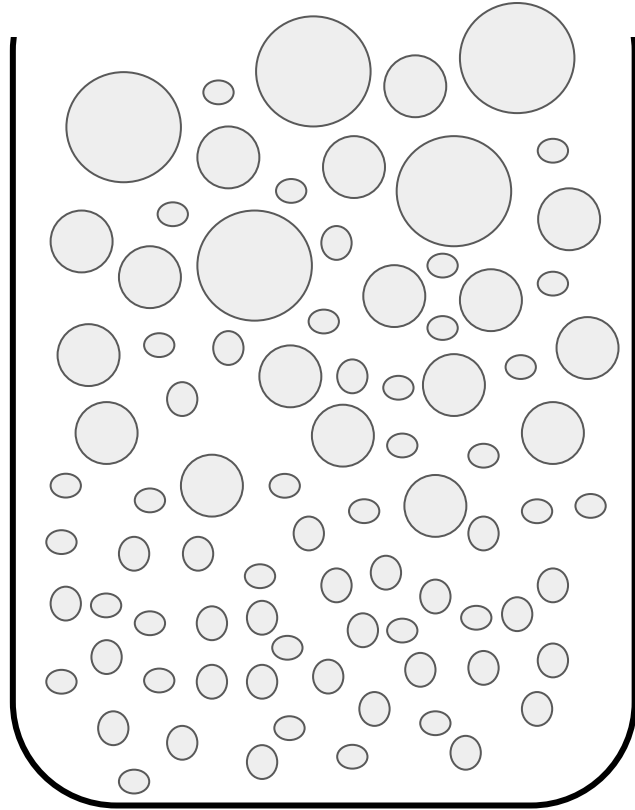
Not recommended if the sample is soluble in water.

Not recommended if the water reacts with water.
Another solvent has to be considered.

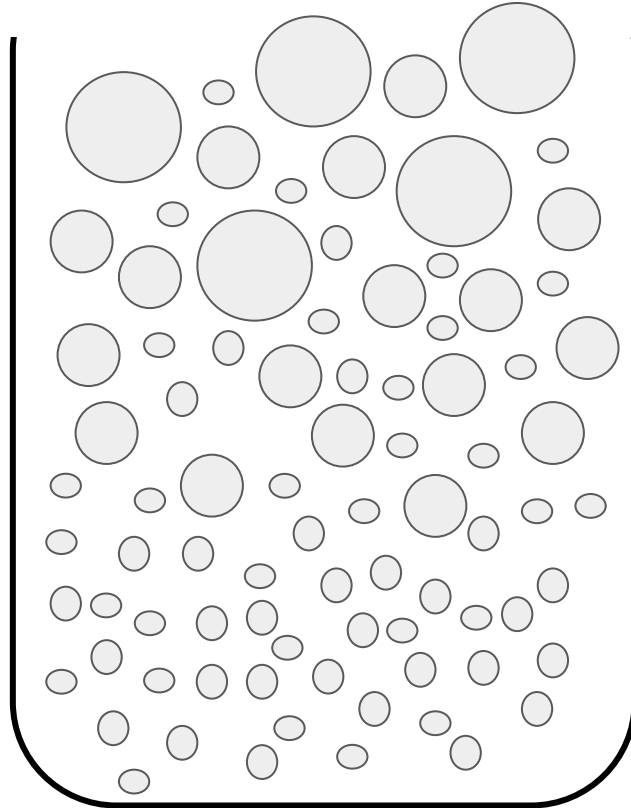
Air circulation jet sieving



Size migration in a container



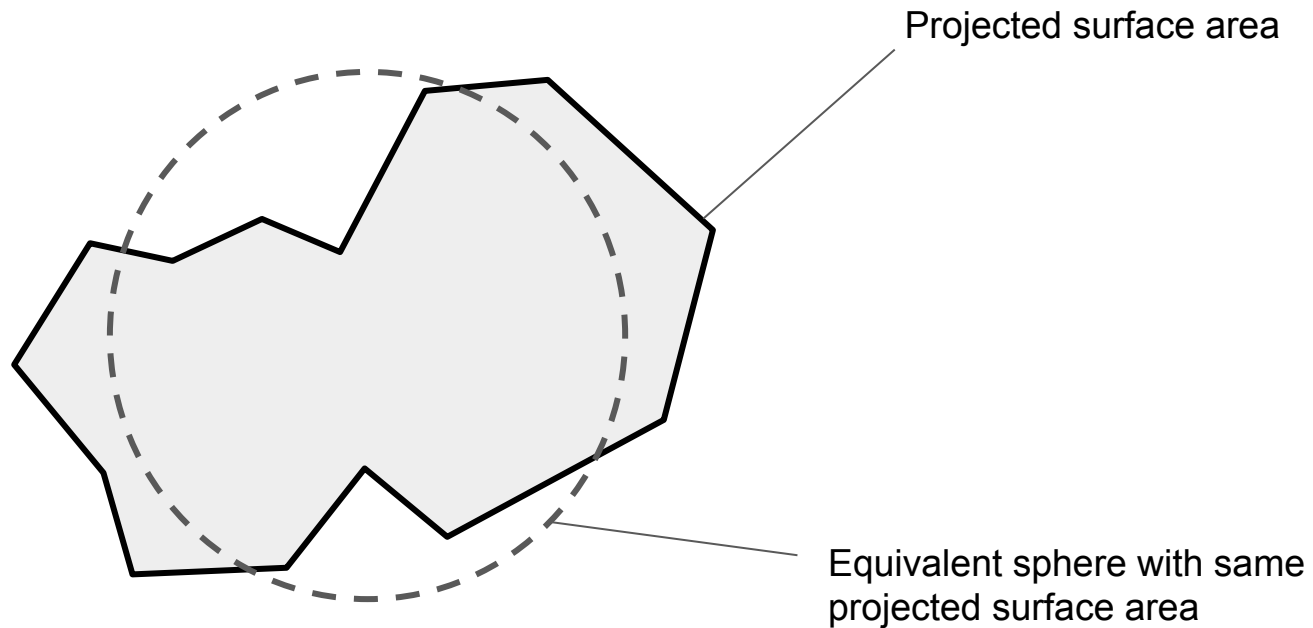
Size migration in a container



To mix it we flip the container 10 times.

Measuring size distribution

Size distribution characterization



Size distribution characterization

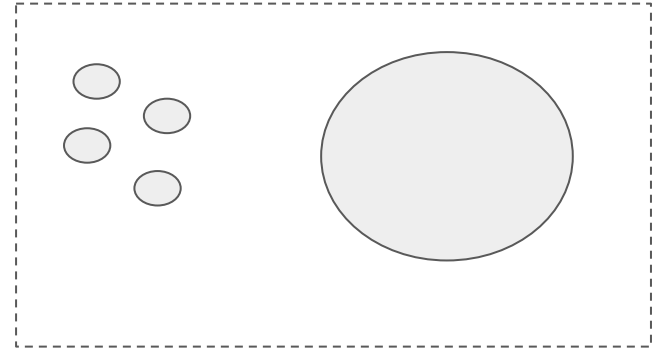
Number distributions

$$N = \int_0^{\infty} \nu(r) dr$$

↑
Total number of spheres per unit volume

Number of spheres per unit volume having a size between r and $r+dr$

Number distribution



$$n(r) = \nu(r)/N \quad \longrightarrow \quad \int_0^{\infty} n(r) dr = 1$$

↑
Normalized number distribution

Size distribution characterization

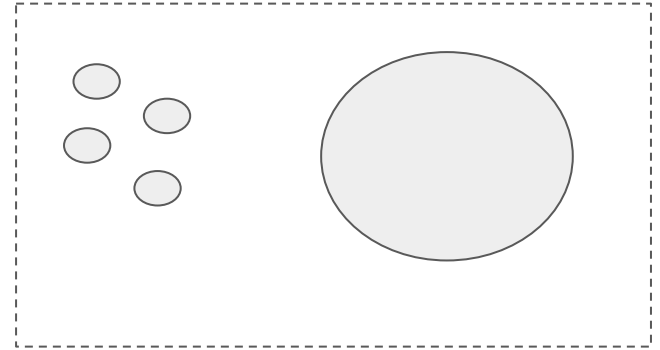
Volume distributions

$$V = \int_0^{\infty} \nu(r) \left(\frac{4}{3} \pi r^3 \right) dr$$

Total volume occupied by the sample

$$v(r) = \frac{\nu(r) \frac{4}{3} \pi r^3}{V}$$

Normalized volume distribution



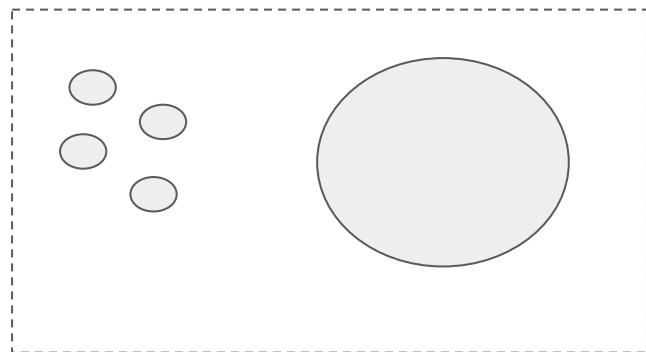
$$\int_0^{\infty} v(r) dr = 1$$

Size distribution characterization

Projected-surface-area distributions

$$\frac{\int_{r_1}^{r_2} \nu(r) \pi r^2 dr}{\int_0^{\infty} \nu(r) \pi r^2 dr} = \frac{\int_{r_1}^{r_2} \nu(r) \pi r^2 dr}{S} = \int_{r_1}^{r_2} s(r) dr$$

Projected-surface-area distribution



$$s(r) = \frac{\nu(r) \pi r^2}{S} = \frac{\nu(r) r^2}{\int_0^{\infty} \nu(r) r^2 dr} \longrightarrow \int_0^{\infty} s(r) dr = 1$$

Normalized projected-surface-area distribution

Size distribution characterization

$$r_{\text{eff}} = \frac{\int_0^{\infty} r \pi r^2 n(r) \, dr}{\int_0^{\infty} \pi r^2 n(r) \, dr} = \frac{3 V}{4 S} = \int_0^{\infty} r s(r) \, dr$$

Used as weighting function

$$\sigma_{\text{eff}} = \sqrt{\frac{\int_0^{\infty} (r - r_{\text{eff}})^2 \pi r^2 n(r) \, dr}{r_{\text{eff}}^2 \int_0^{\infty} \pi r^2 n(r) \, dr}} = \sqrt{\frac{\int_0^{\infty} (r - r_{\text{eff}})^2 s(r) \, dr}{r_{\text{eff}}^2 \int_0^{\infty} s(r) \, dr}}$$

Size distribution characterization

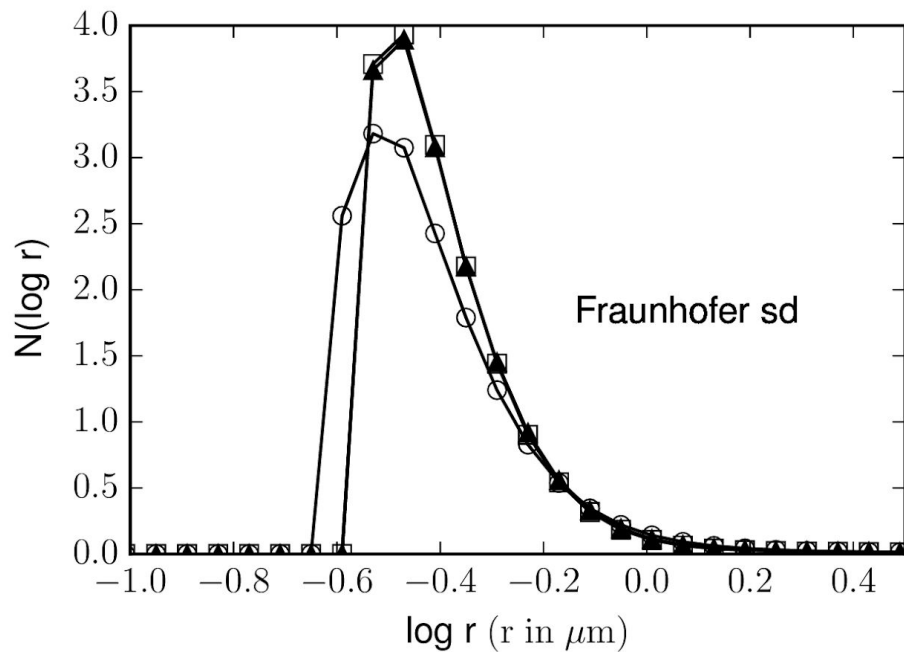
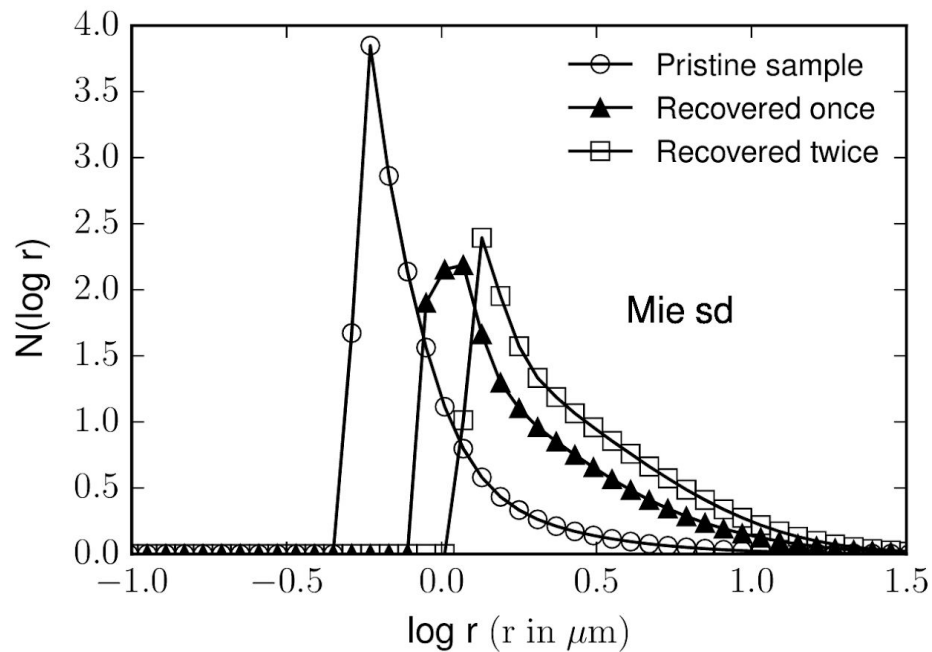
$$\int_{r_1}^{r_2} n(r) dr = \int_{\log r_1}^{\log r_2} N(\log r) d \log r = \int_{r_1}^{r_2} \left[N(\log r) \frac{d \log r}{dr} \right] dr = \int_{r_1}^{r_2} \frac{N(\log r)}{r \ln 10} dr$$

$$N(\log r) = \ln 10 r n(r) = 2.303 r n(r)$$

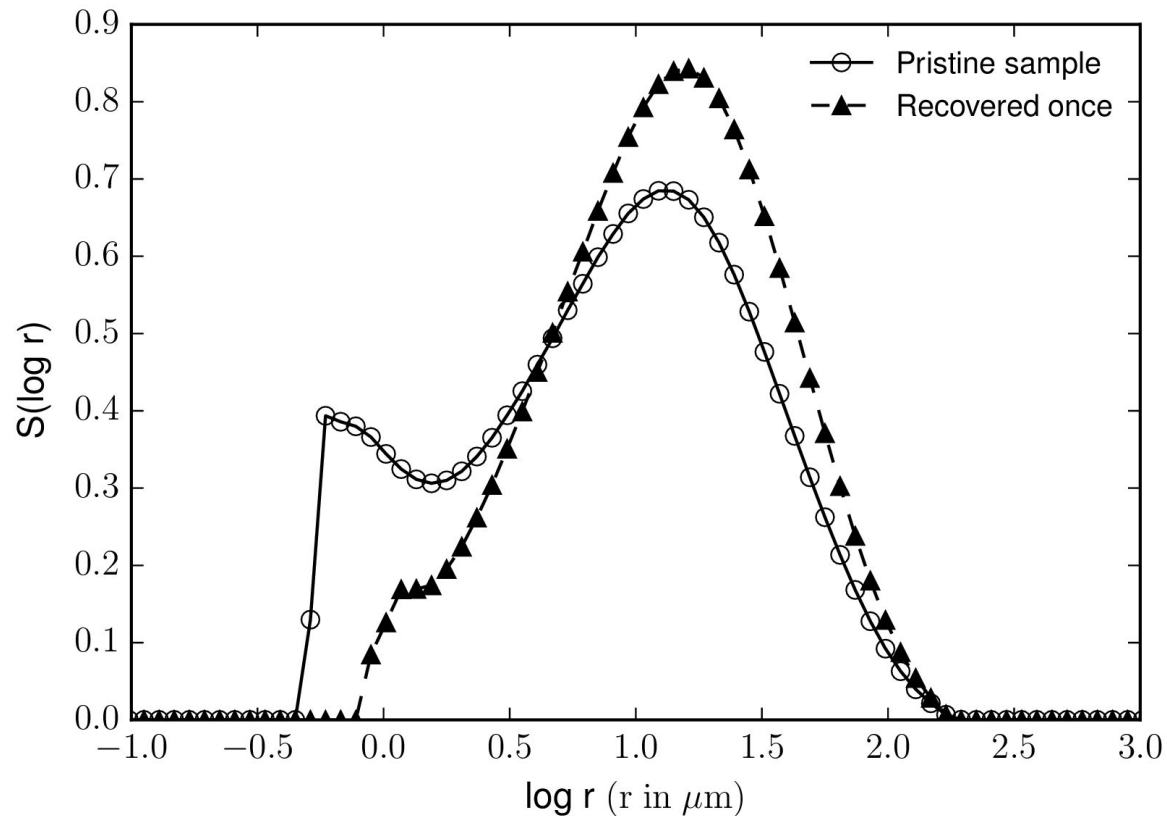
$$S(\log r) = \ln 10 r s(r) = 2.303 r s(r)$$

$$V(\log r) = \ln 10 r v(r) = 2.303 r v(r)$$

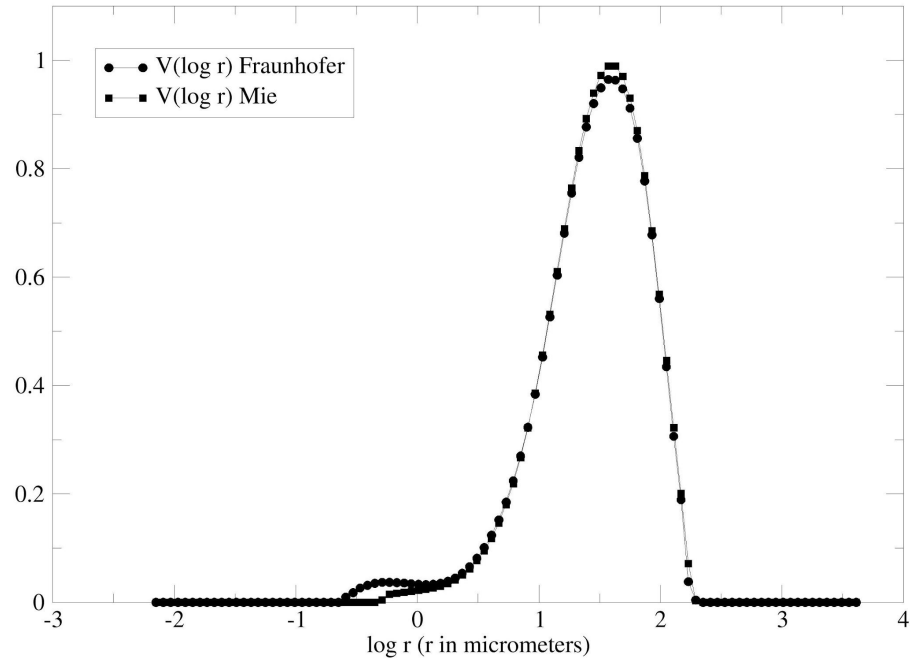
Size distribution characterization



Size distribution characterization



Size distribution characterization



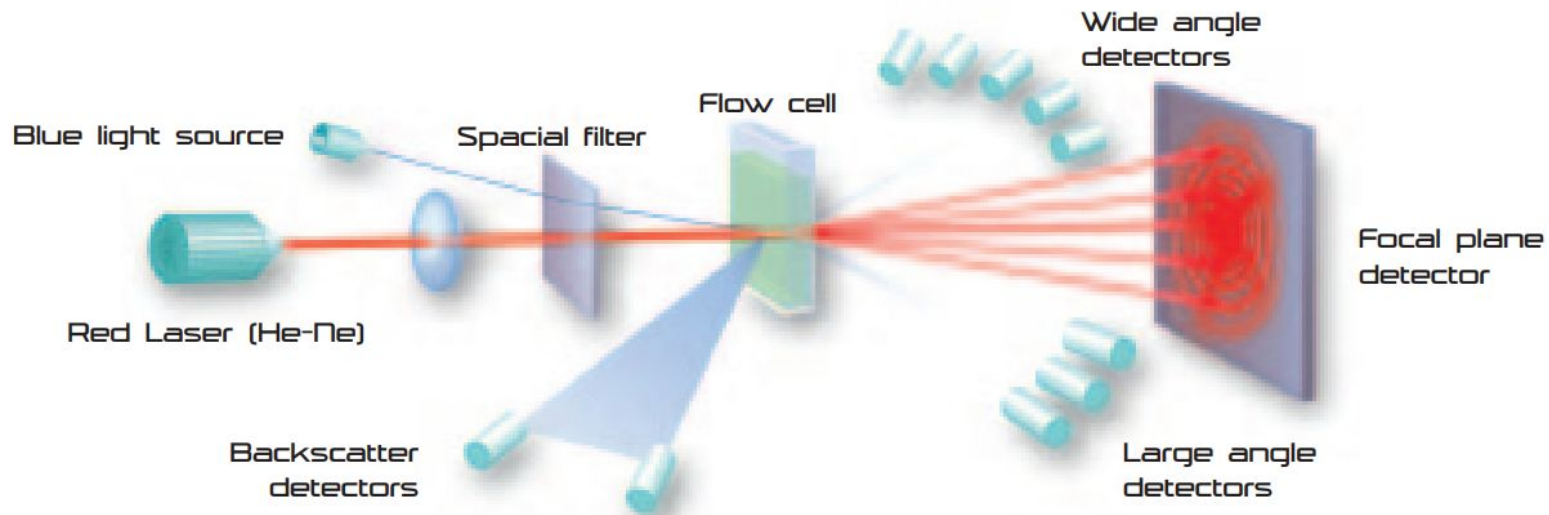
Size distribution characterization



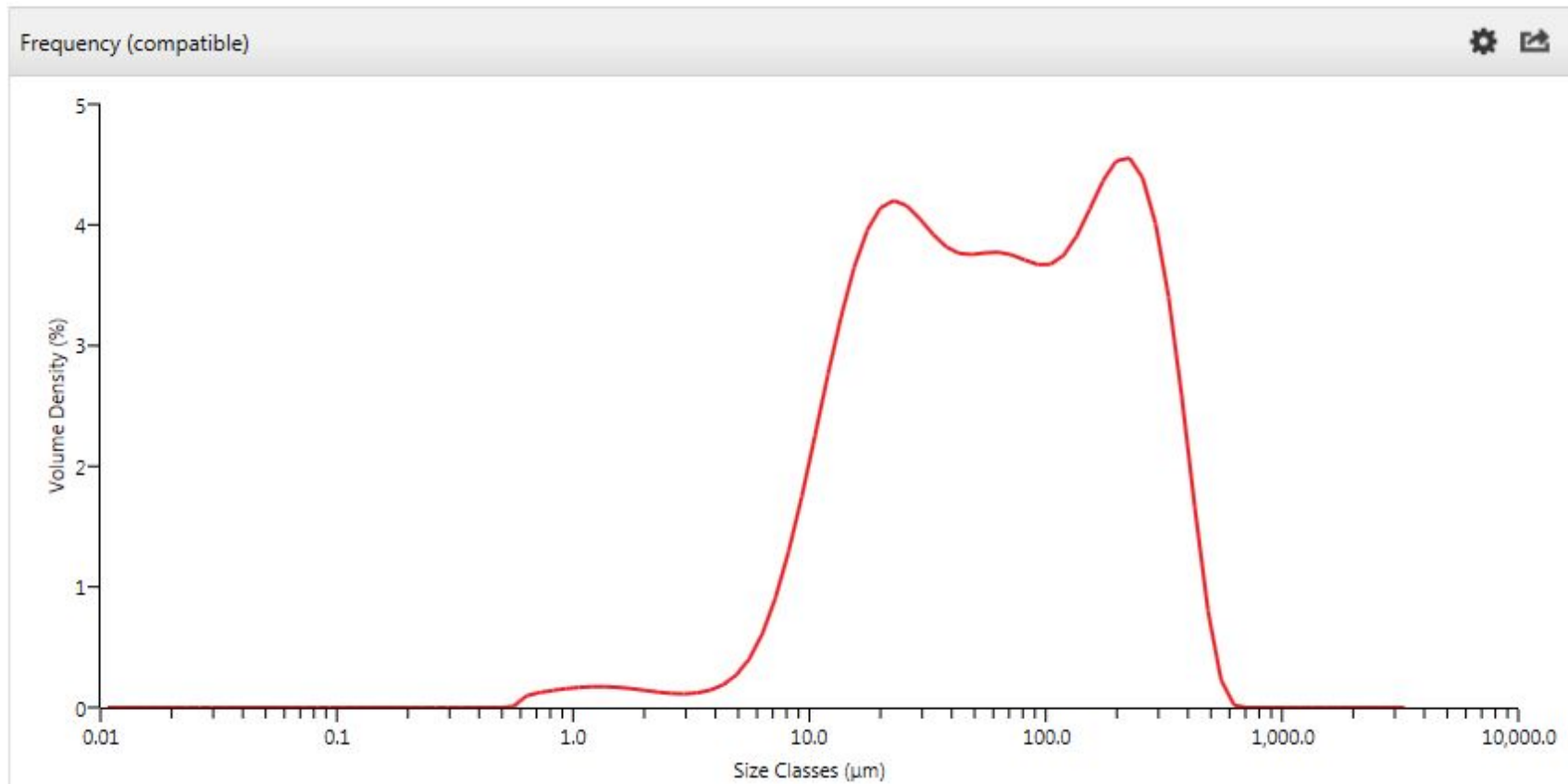
Mastersizer 2000 from Malvern Instruments

Size distribution characterization

Fundamentals of the technology



Size distribution characterization



Characterizing the structure: SEM and FESEM

SEM and FESEM

SEM: Scanning Electron Microscopy

FESEM: Field Emission Scanning Electron Microscopy

SEM and FESEM

Here in the University of Helsinki you can find these services at:

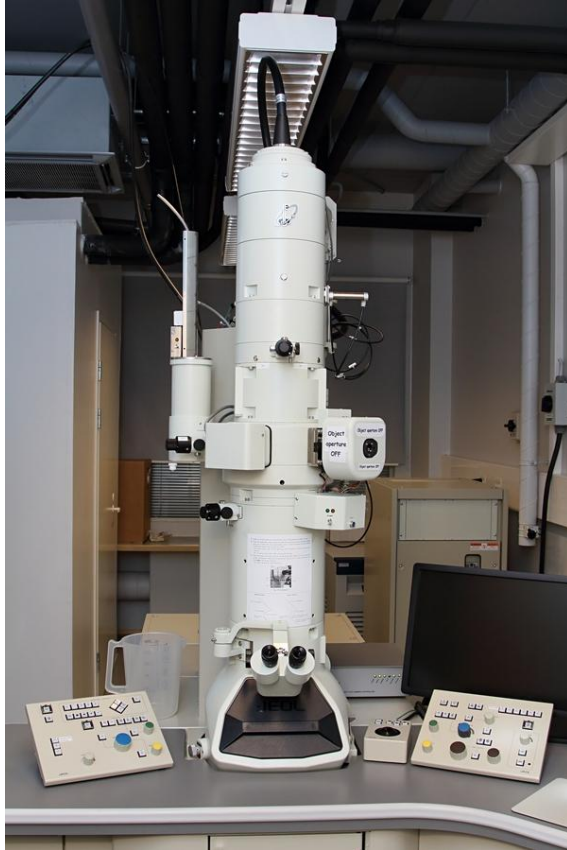
- EMBI: Electron Microscopy Institute of Biotechnology at Viikki Campus offers both SEM and FESEM
- In the laboratory of nanomaterials (Helsinki Accelerator Laboratory, Kumpula Campus) they offer Atomic Force Microscopy (AFM) and Scanning Tunneling Microscopy (STM) just to mention a couple of examples.

SEM and FESEM

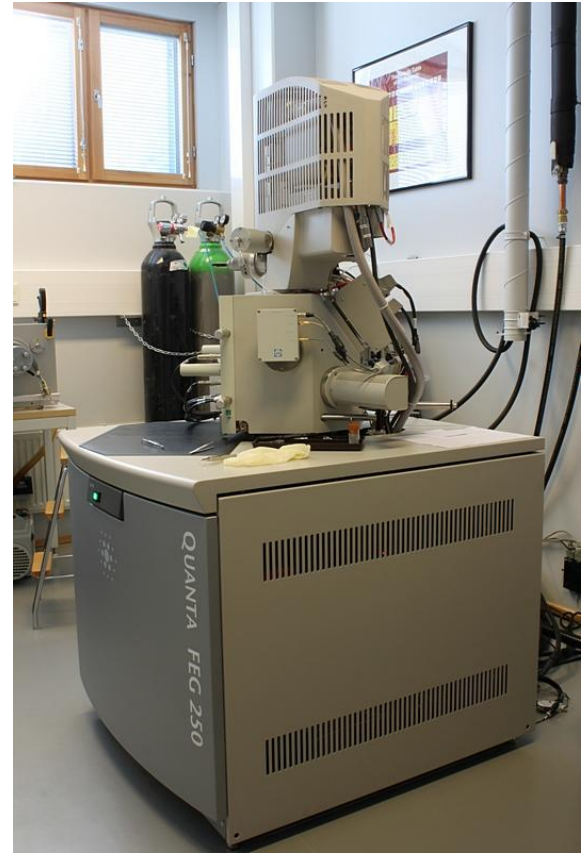


Hitachi S-510 SEM

SEM and FESEM



Jeol JEM-1400 Transmission Electron Microscope



FEI Quanta 250 Field Emission Gun Scanning Electron Microscope

SEM and FESEM

SEM stubs

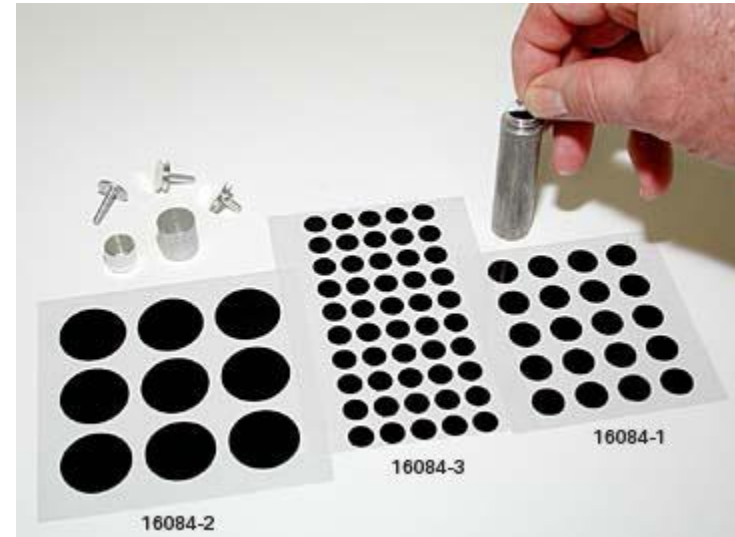


SEM and FESEM

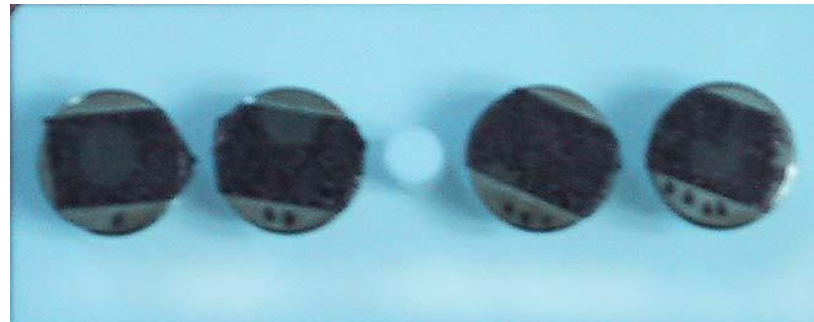
SEM stubs



SEM and FESEM



Carbon conductive tape

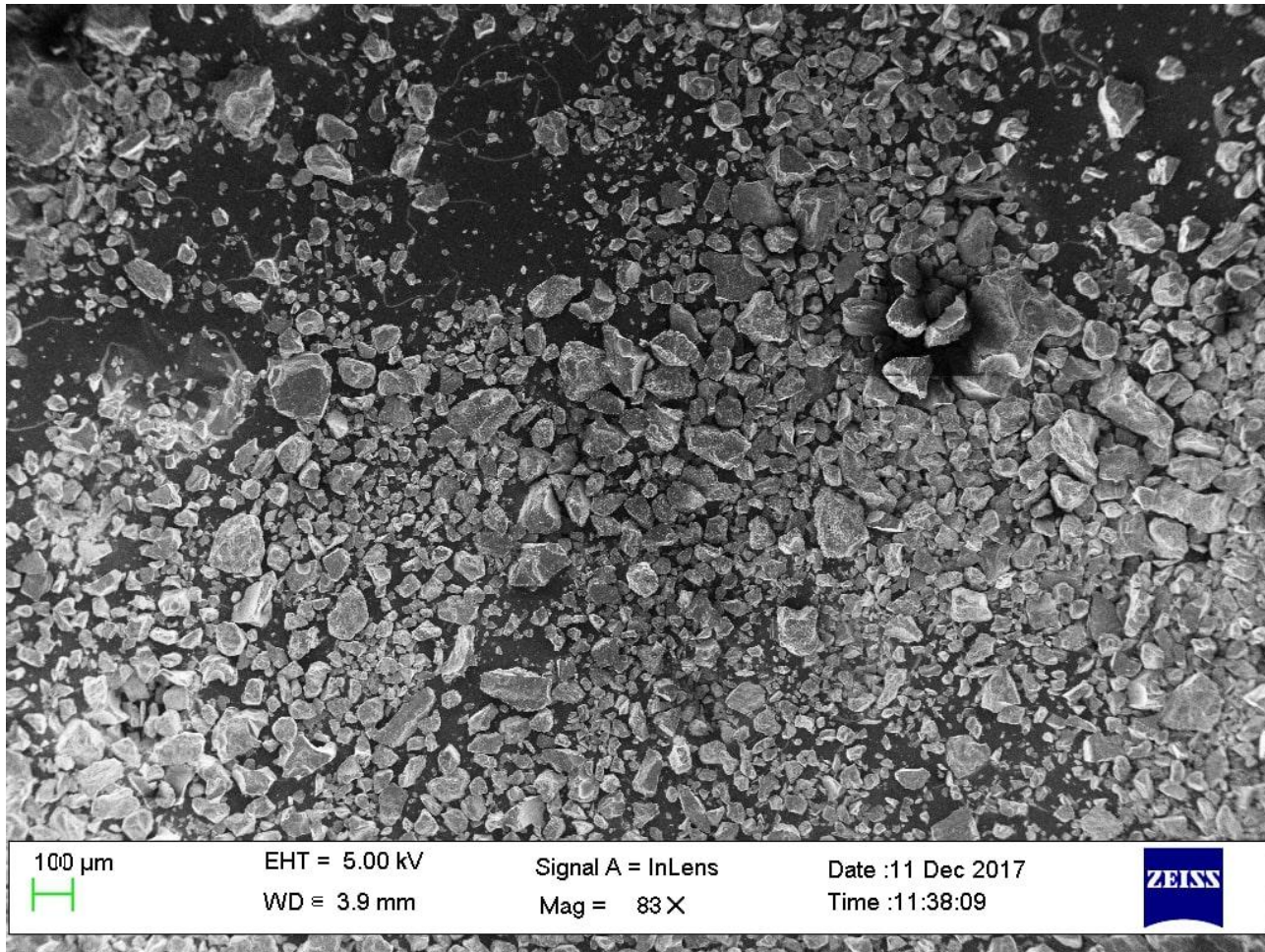


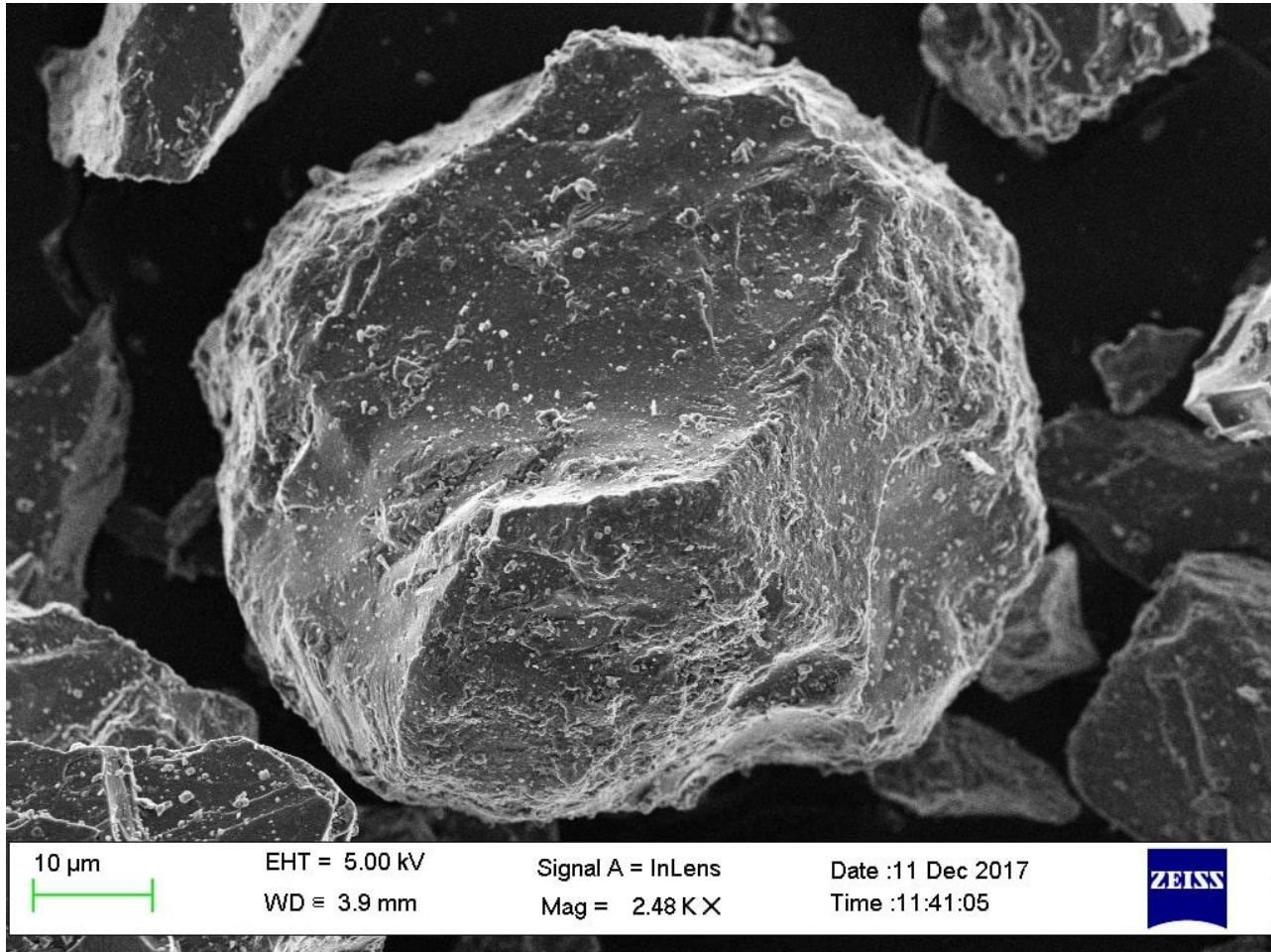
SEM and FESEM

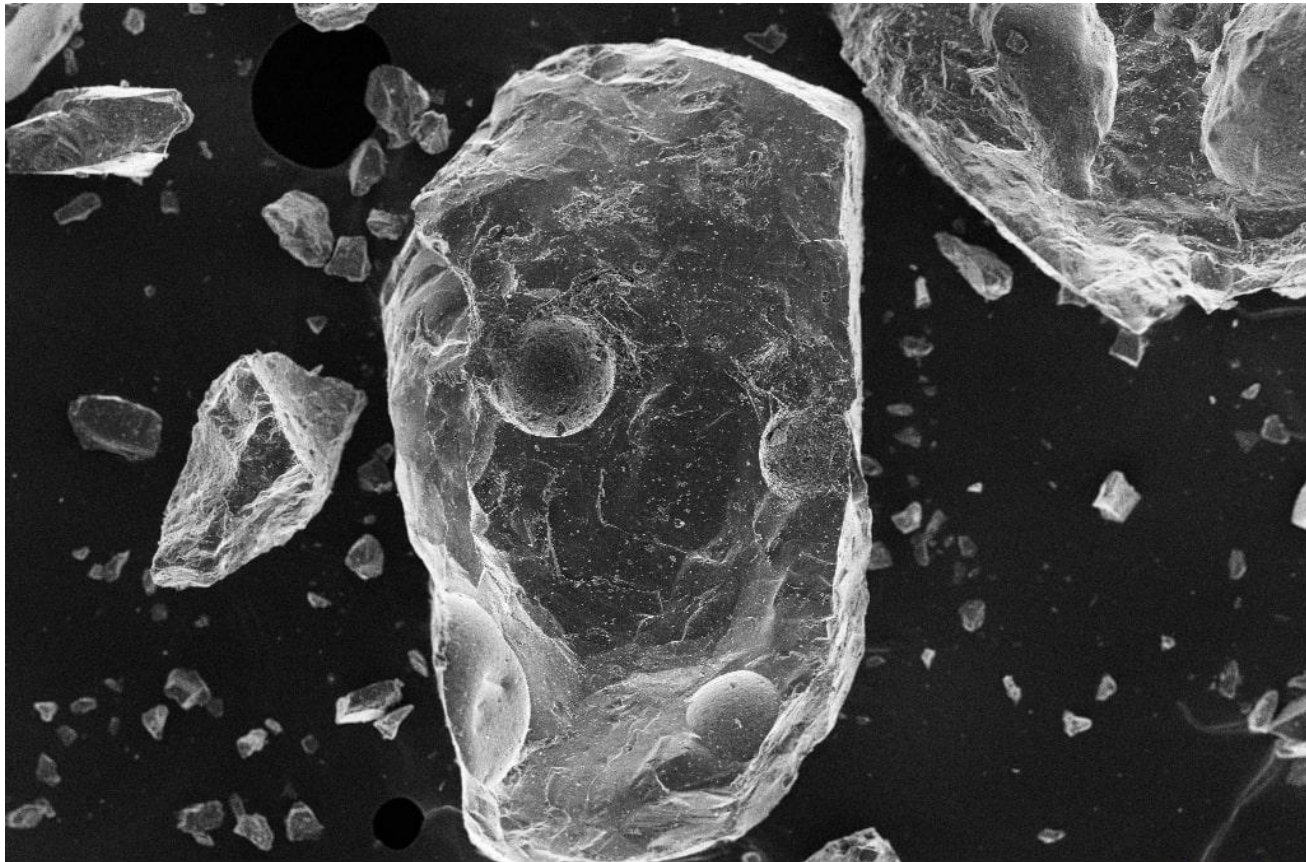


Platinum or carbon coating. Nonconductive specimens collect charge when scanned by the electron beam. This causes scanning faults and other image artifacts. **Specimens must be electrically conductive**, at least at the surface, and electrically grounded to prevent the accumulation of electrostatic charge.

SEM and FESEM







20 μ m



EHT = 5.00 kV

WD = 3.8 mm

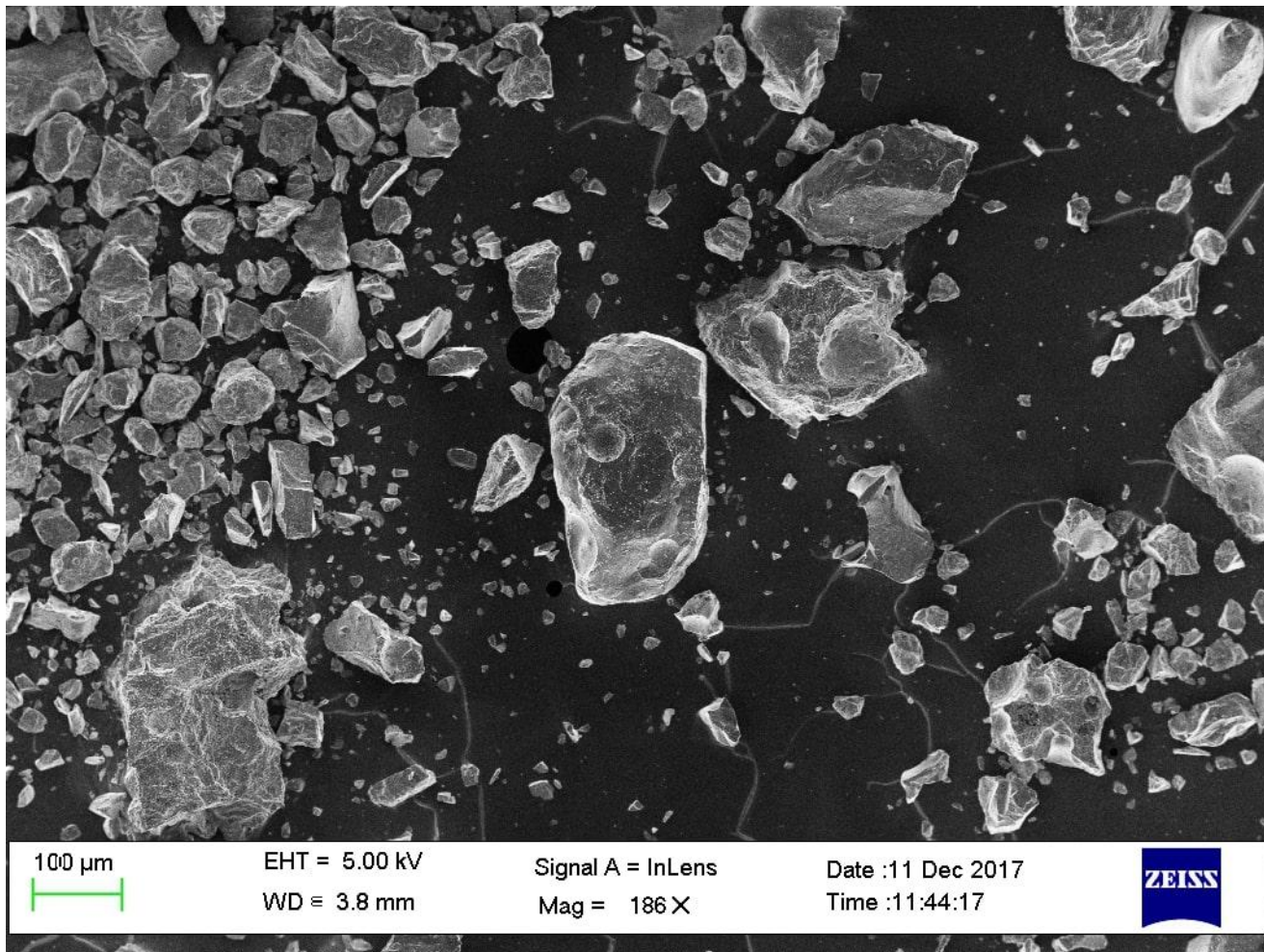
Signal A = InLens

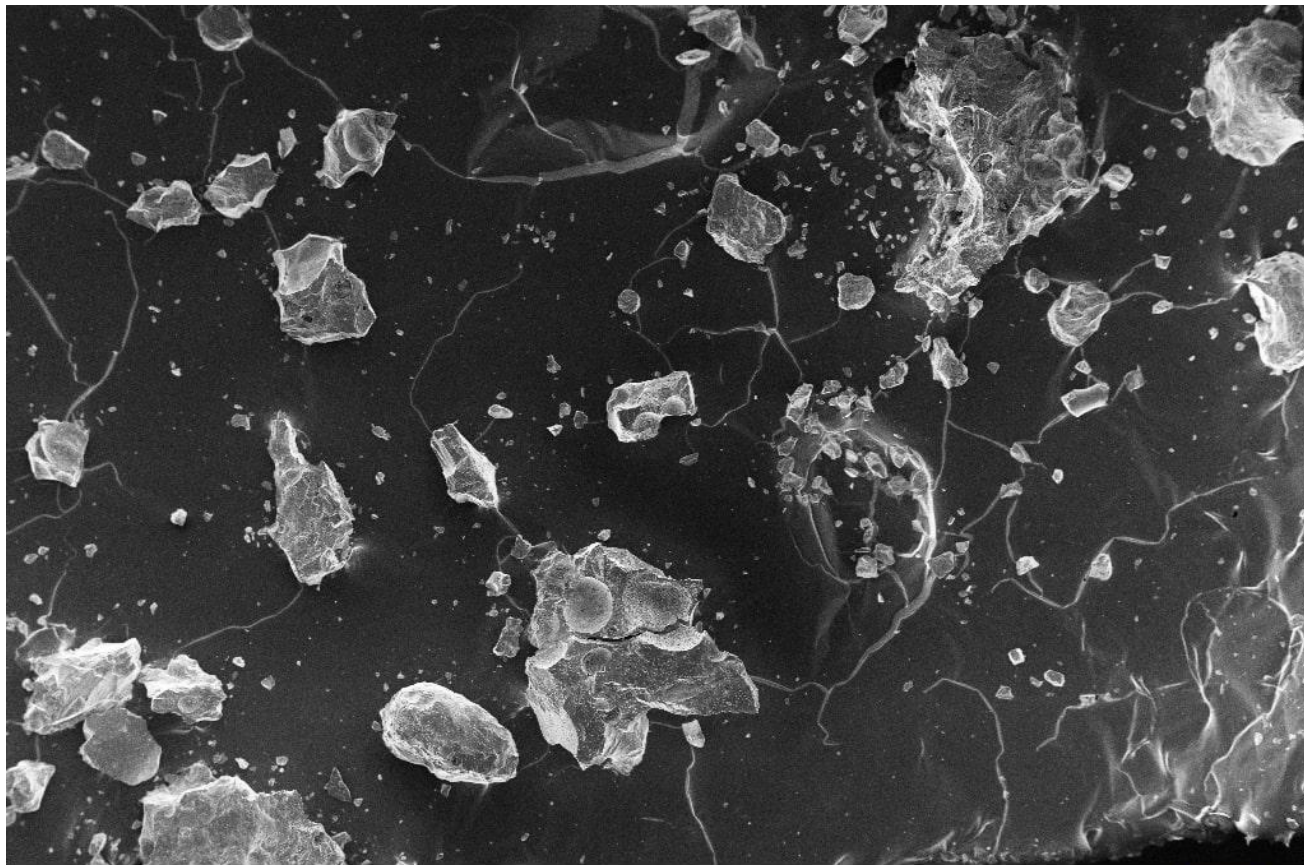
Mag = 549 X

Date :11 Dec 2017

Time :11:43:34







100 μ m



EHT = 5.00 kV

WD = 3.8 mm

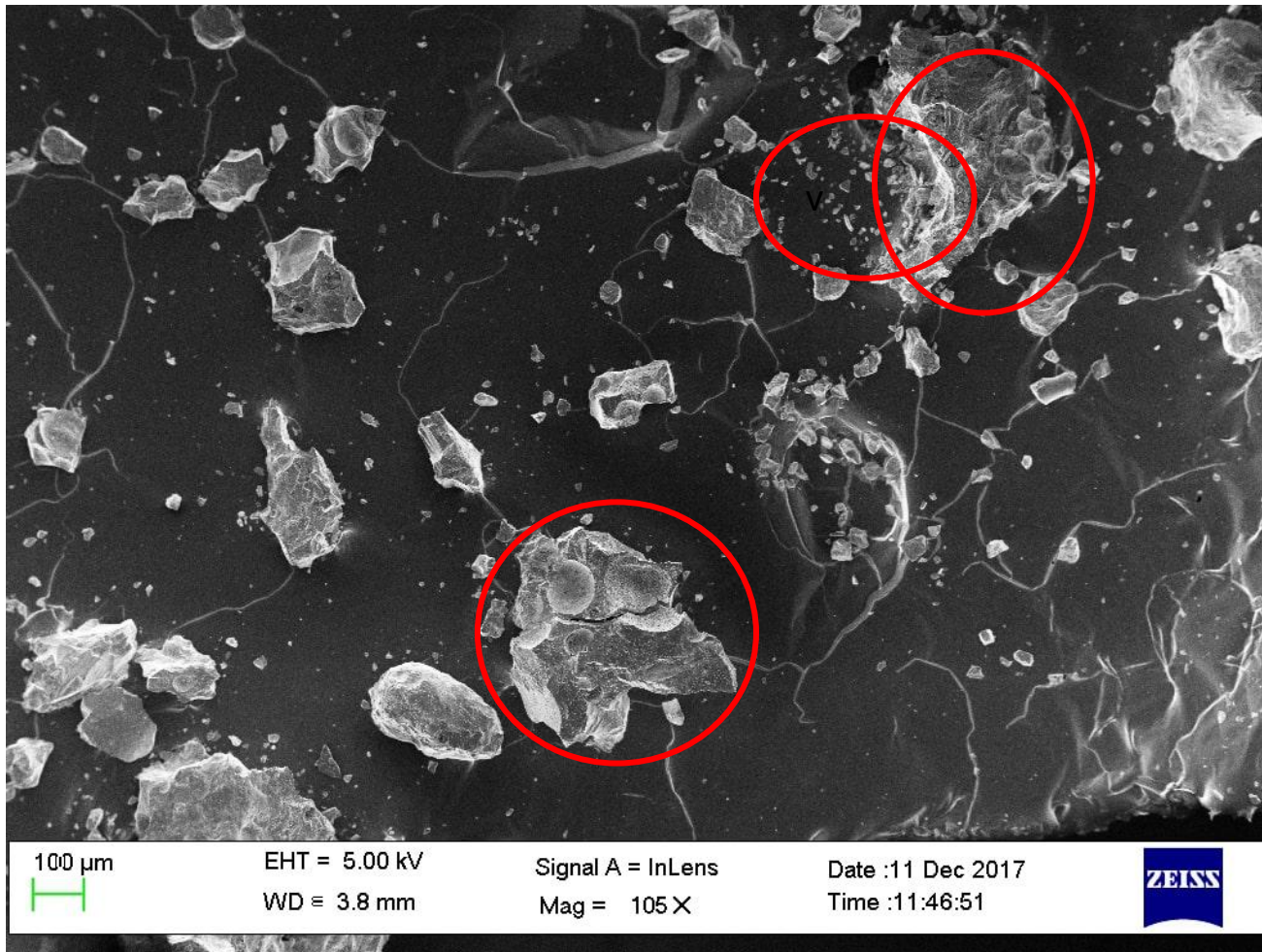
Signal A = InLens

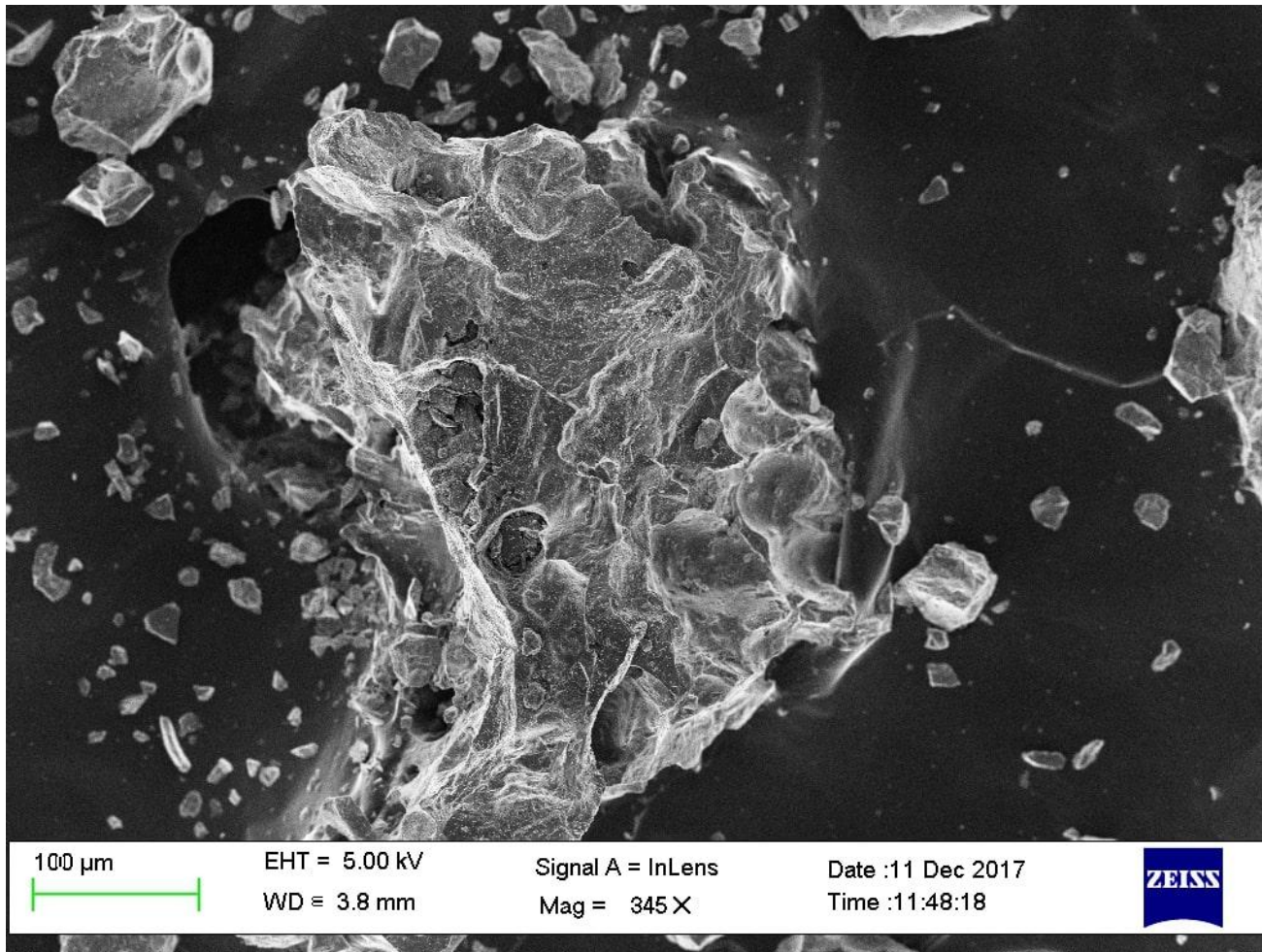
Mag = 105 X

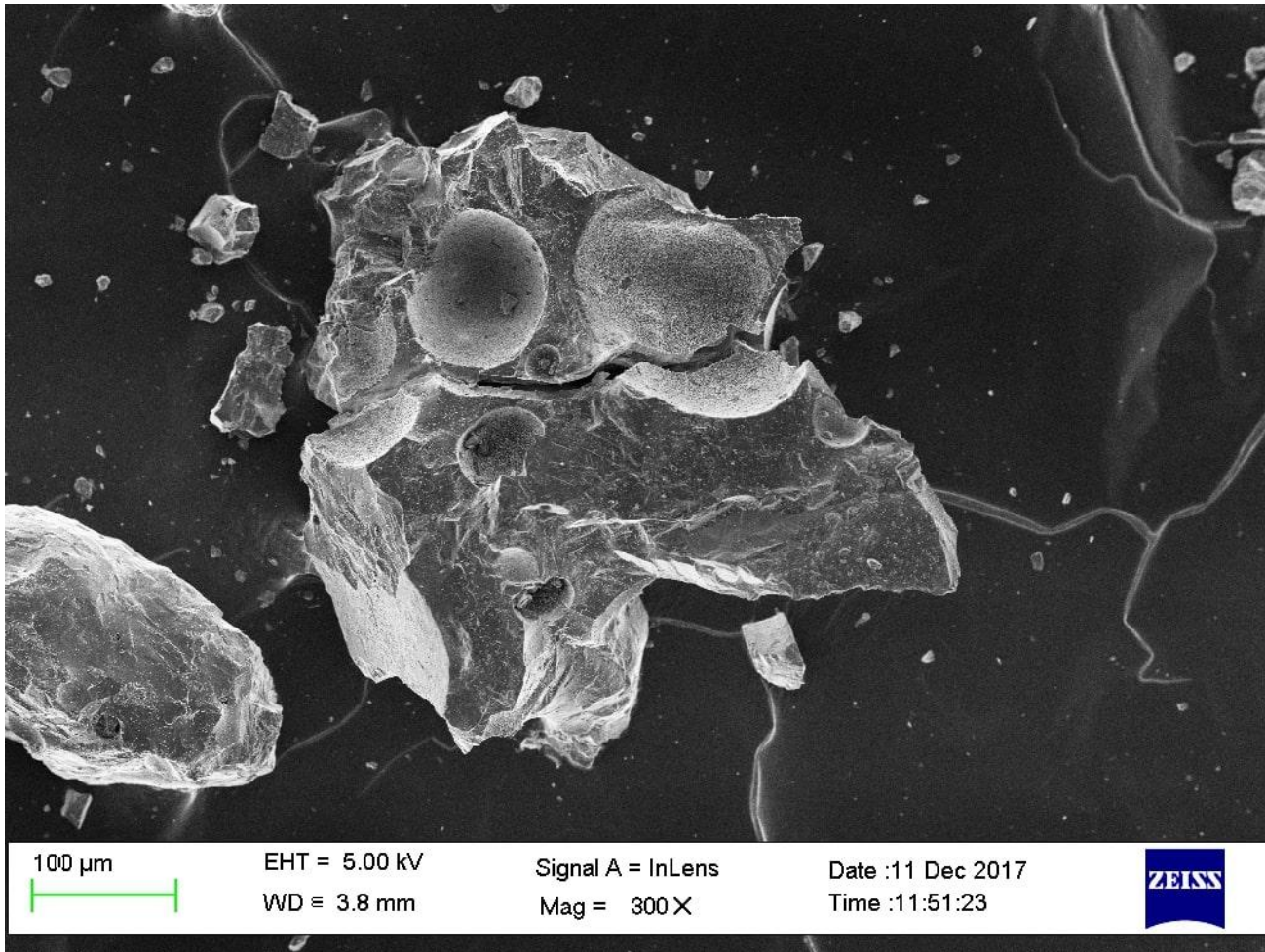
Date :11 Dec 2017

Time :11:46:51

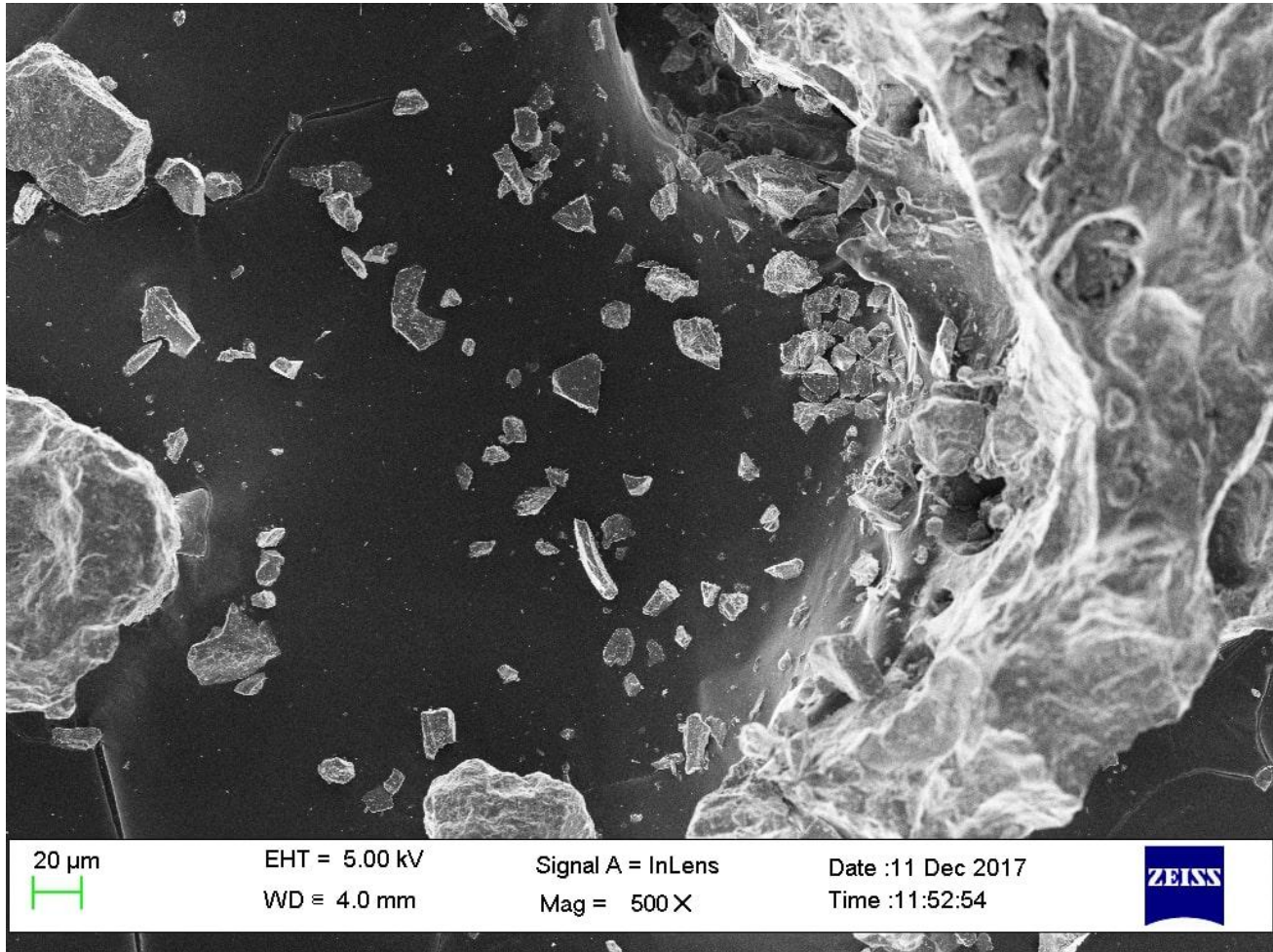


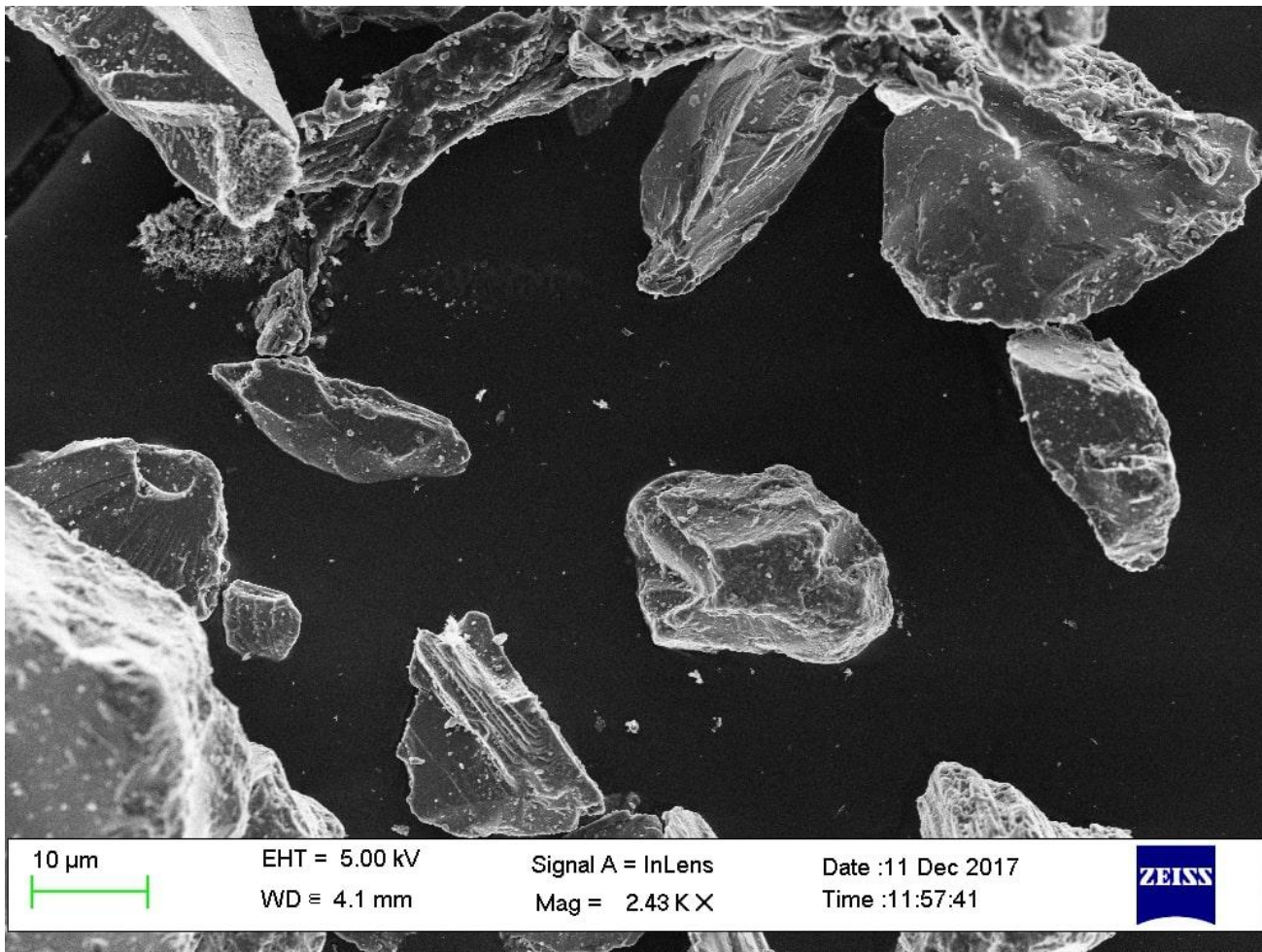


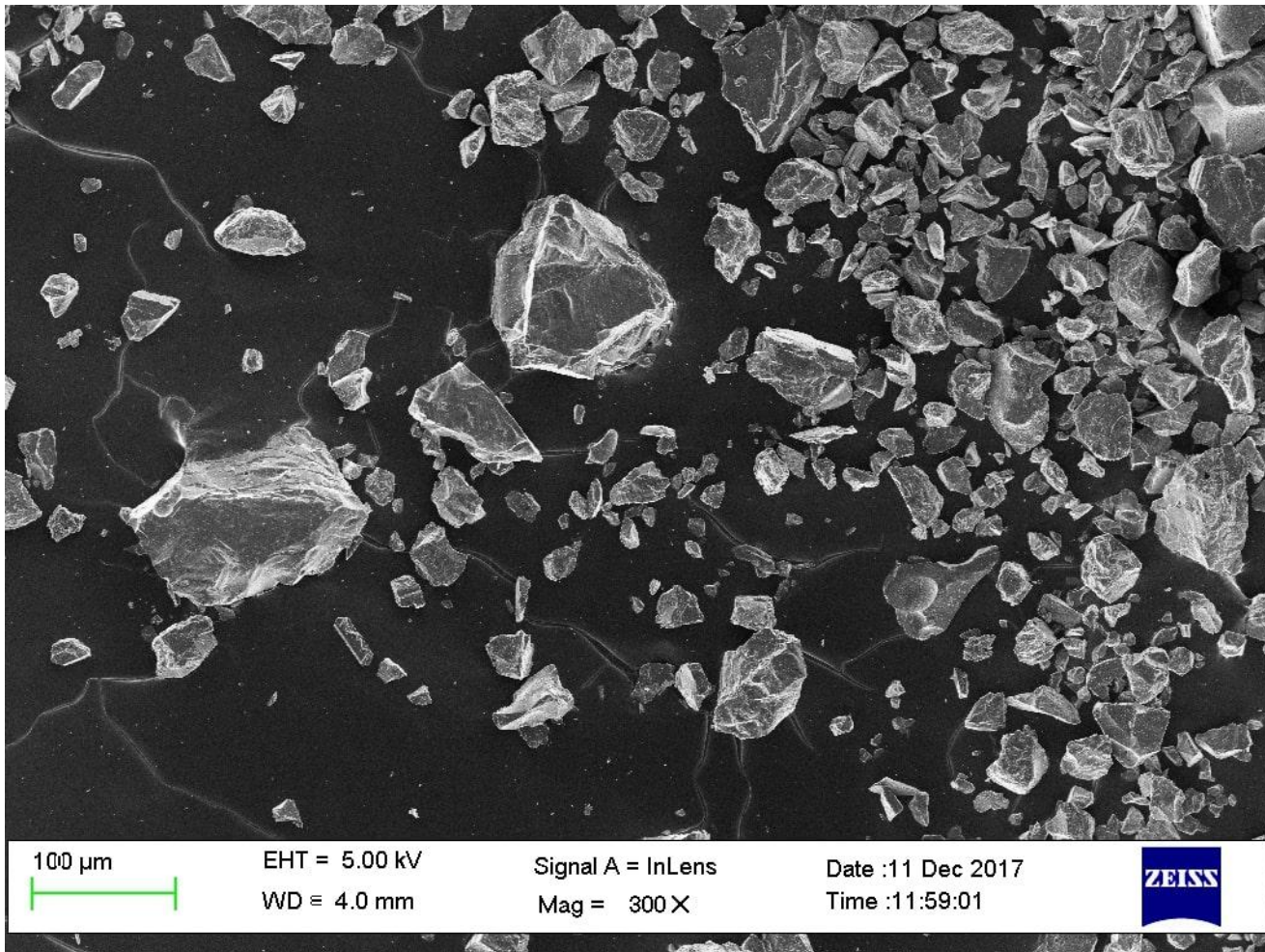




SEM and FESEM







Cosmic dust analogs

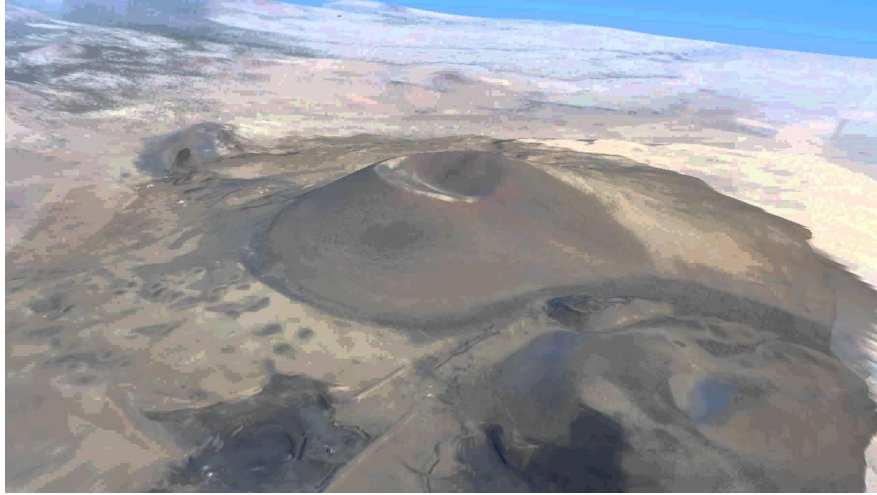
Cosmic dust analogs: Geomorphology



Arizona,
USA



Cosmic dust analogs: Geochemistry



Merriam crater, Arizona

Constituent oxides	Apollo 14 sample 14163 (Papike et al. 1982)	JSC-1A (Ray et al. 2010)
SiO ₂	47.3 %	45.7 %
Al ₂ O ₃	17.8 %	16.2 %
CaO	11.4 %	10.0 %
FeO	10.5 %	-
Fe ₂ O ₃	-	12.4 %
MgO	9.6 %	8.7 %
TiO ₂	1.6 %	1.9 %
Na ₂ O	0.70 %	3.2 %
K ₂ O	0.55 %	0.8 %
MnO	0.135 %	0.2 %

Cosmic dust analogs: Geochemistry



Mauna Loa, Hawaii



Cosmic dust analogs: Exobiology



Río Tinto, Spain



High temperature and harsh chemical conditions.

Cosmic dust analogs: Exobiology



Concordia station, Antarctica
-40 °C

Cosmic dust analogs: Exobiology



Atacama desert, Chile

Laboratory daily procedures

Laboratory daily procedures

For your own safety



Laboratory daily procedures

For the safety of your laboratory

